

Seminář odd. 26

Tenkých vrstev a nanostruktur

Fyzikální ústav AVČR, Cukrovarnická 10, Praha 6

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TÉMA

Atomic scale characterisation of pentacene and C60 on the anatase (101) surface using atomic force microscopy

Oscar Custance

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Anatase is a pivotal material in devices for energy-harvesting applications and catalysis. Here, we will present a study that combines atomic force microscopy and scanning tunnelling microscopy, supported by first-principles calculations, for the simultaneous imaging and identification of atomic species at the (101) anatase surface. We will also present a high-resolution imaging method that enabled us to characterise the adsorption geometry of pentacene and C60 molecules deposited on the anatase (101) surface in the sub-monolayer coverage regime.

odborný garant: *Ing. Pavel Jelínek, Ph.D.*